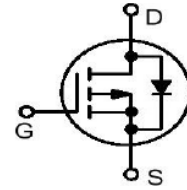


### Features

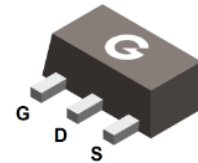
- $R_{DS(ON)} \leq 52m\Omega @ V_{GS} = -10V$
- $R_{DS(ON)} \leq 87m\Omega @ V_{GS} = -4.5V$
- High-speed switching
- Drive circuits can be simple
- Parallel use is easy
- JESD22-A114-B ESD rating of class 0 per human body model

HF



### Typical Applications

- Power Management in Note Book
- Switching Application
- Battery Powered System
- Load switch



### Mechanical Data

- Case: SOT-89
- Molding Compound, UL Flammability Classification Rating 94V-0
- Terminals: Matte Tin Plated Leads, Solderable Per MIL-STD-202, Method 208

SOT-89

### Ordering Information

Part Number	Package	Shipping Quantity	Marking Code
BL3407E	SOT-89	1000 pcs / Tape & Reel	3407

### Maximum Ratings (@ $T_A = 25^\circ\text{C}$ unless otherwise specified)

Parameter	Symbol	Value	Unit	
Drain-Source Voltage	$V_{DSS}$	-30	V	
Gate -Source Voltage	$V_{GSS}$	$\pm 20$	V	
Continuous Drain Current	$I_D$	$T_A = 25^\circ\text{C}$	-5.3	A
		$T_A = 70^\circ\text{C}$	-4.2	A
Pulsed Drain Current ( $t_p = 10\mu\text{s}$ , $T_A = 25^\circ\text{C}$ )	$I_{DM}$	-20	A	
Single Pulse Avalanche Energy <sup>3</sup>	$E_{AS}$	12	mJ	
Power Dissipation	$P_D$	$T_A = 25^\circ\text{C}$	2	W
		$T_C = 25^\circ\text{C}$	4	W
Operating Junction Temperature Range	$T_J$	-55 ~ +150	$^\circ\text{C}$	
Storage Temperature Range	$T_{STG}$	-55 ~ +150	$^\circ\text{C}$	

### Thermal Characteristics

Parameter	Symbol	Min.	Typ.	Max.	Unit
Thermal Resistance Junction-to-Case	$R_{\theta JC}$	-	20	30	$^{\circ}\text{C/W}$
Thermal Resistance Junction-to-Air <sup>*1</sup>	$R_{\theta JA}$	-	45	60	$^{\circ}\text{C/W}$

### Electrical Characteristics (@ $T_A = 25^{\circ}\text{C}$ unless otherwise specified)

Symbol	Parameter	Test Condition	Min.	Typ.	Max.	Unit
<b>Static Characteristics</b>						
$V_{DSS}$	Drain-Source Breakdown Voltage	$V_{GS} = 0\text{V}, I_D = -250\mu\text{A}$	-30	-	-	V
$I_{DSS}$	Zero Gate Voltage Drain Current	$V_{DS} = -24\text{V}, V_{GS} = 0\text{V}$	-	-	-1	$\mu\text{A}$
$I_{GSS}$	Gate-Body Leakage Current	$V_{GS} = \pm 20\text{V}, V_{DS} = 0\text{V}$	-	-	$\pm 100$	nA
<b>On Characteristics</b>						
$R_{DS(ON)}$	Drain-Source On-resistance <sup>*2</sup>	$V_{GS} = -10\text{V}, I_D = -4.1\text{A}$	-	-	52	m $\Omega$
		$V_{GS} = -4.5\text{V}, I_D = -3\text{A}$	-	-	87	m $\Omega$
$V_{GS(th)}$	Gate Threshold Voltage	$V_{DS} = V_{GS}, I_D = -250\mu\text{A}$	-1	-1.5	-3	V
$R_G$	Gate Resistance	$V_{GS} = 0\text{V}, f = 1\text{MHz}$	-	12	-	$\Omega$
<b>Dynamic Characteristics</b>						
$g_{FS}$	Forward Transconductance	$V_{DS} = -5\text{V}, I_D = -4\text{A}$	-	7	-	S
$C_{ISS}$	Input Capacitance	$V_{GS} = 0\text{V}$ $V_{DS} = -15\text{V}$ $f = 1.0\text{MHz}$	-	793	-	pF
$C_{OSS}$	Output Capacitance		-	78	-	
$C_{RSS}$	Reverse Transfer Capacitance		-	61	-	
<b>Switching Characteristics</b>						
$t_{d(ON)}$	Turn-on Delay Time <sup>*4</sup>	$V_{DD} = -15\text{V}, V_{GS} = -10\text{V}$ $R_G = 2.5\Omega, R_L = 15\Omega$ $I_D = -1\text{A}$	-	5	-	ns
$t_r$	Turn-on Rise Time <sup>*4</sup>		-	6	-	
$t_{d(OFF)}$	Turn-Off Delay Time <sup>*4</sup>		-	28	-	
$t_f$	Turn-Off Fall Time <sup>*4</sup>		-	7	-	
$Q_G$	Total Gate-Charge	$V_{DD} = -20\text{V}$	-	8	-	nC
$Q_{GS}$	Gate to Source Charge	$V_{GS} = -4.5\text{V}$	-	2.6	-	
$Q_{GD}$	Gate to Drain (Miller) Charge	$I_D = -3\text{A}$	-	2.6	-	
<b>Source-Drain Diode Characteristics</b>						
$V_{SD}$	Diode Forward Voltage <sup>*2</sup>	$I_{SD} = -1\text{A}, V_{GS} = 0\text{V}, T_J = 25^{\circ}\text{C}$	-	-0.8	-1.0	V
$t_{rr}$	Reverse Recovery Time	$I_{SD} = -3\text{A}, V_{GS} = 0\text{V}$	-	125	-	ns
$Q_{rr}$	Reverse Recovery Charge	$di/dt = 100\text{A}/\mu\text{s}$	-	110	-	nC

Notes:

- The data tested by surface mounted on a 1 inch<sup>2</sup> FR-4 board with 2OZ copper
- The data tested by pulsed, pulse width  $\leq 300\mu\text{s}$ , duty cycle  $\leq 2\%$
- The  $E_{AS}$  data shows Max. rating. The test condition is  $V_{DD} = -15\text{V}, V_{GS} = -10\text{V}, L = 0.1\text{mH}$
- Guaranteed by design, not subject to production

Ratings and Characteristic Curves (@  $T_A = 25^\circ\text{C}$  unless otherwise specified)

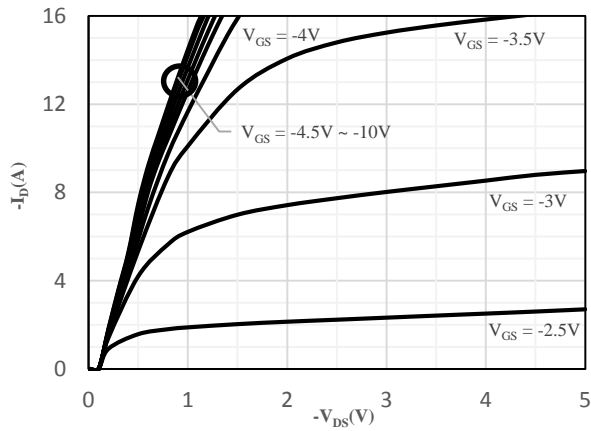


Fig 1 Typical Output Characteristics

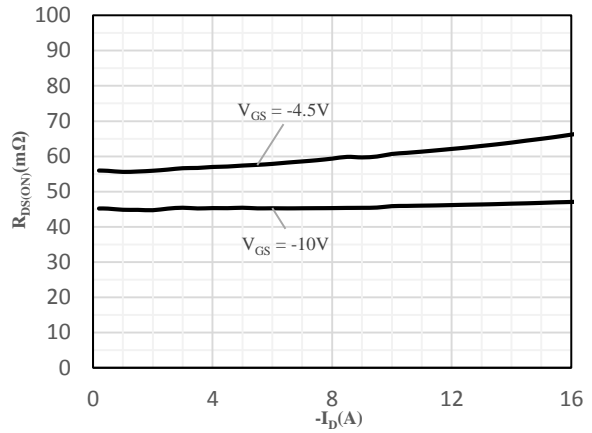


Fig 2 On-Resistance vs. Drain Current and Gate Voltage

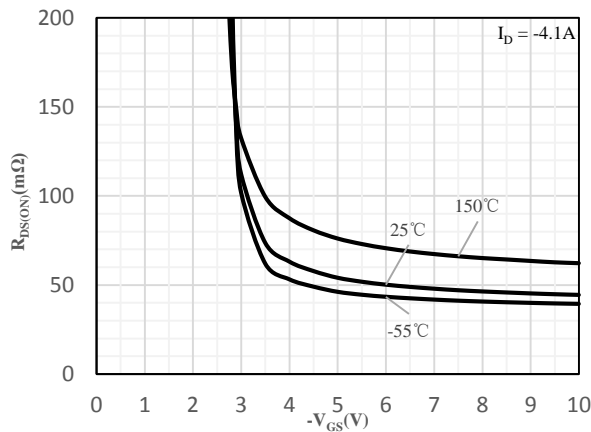


Fig 3 On-Resistance vs. Gate-Source Voltage

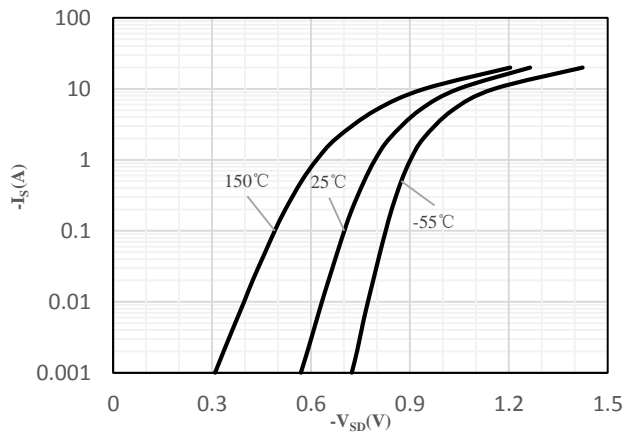


Fig 4 Body-Diode Characteristics

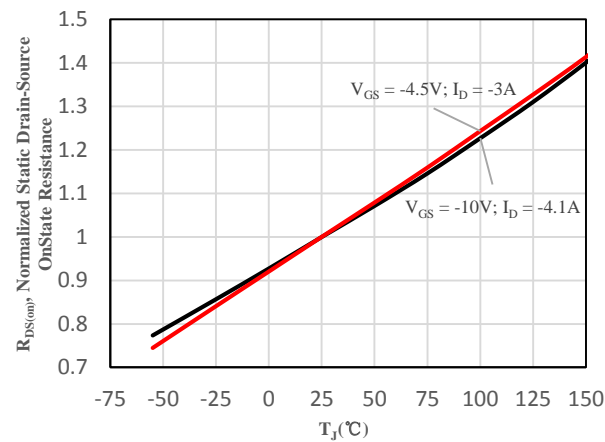


Fig 5 Normalized On-Resistance vs. Junction Temperature

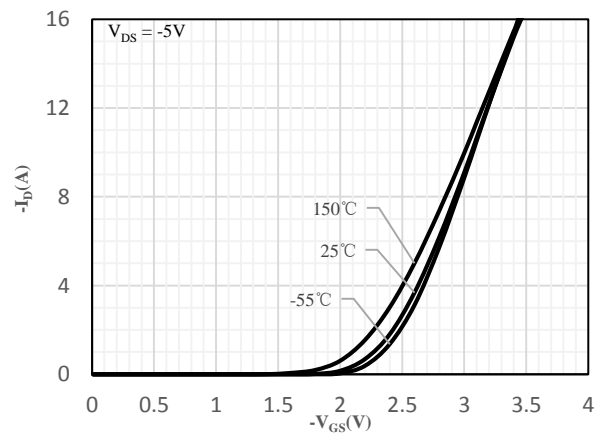


Fig 6 Transfer Characteristics

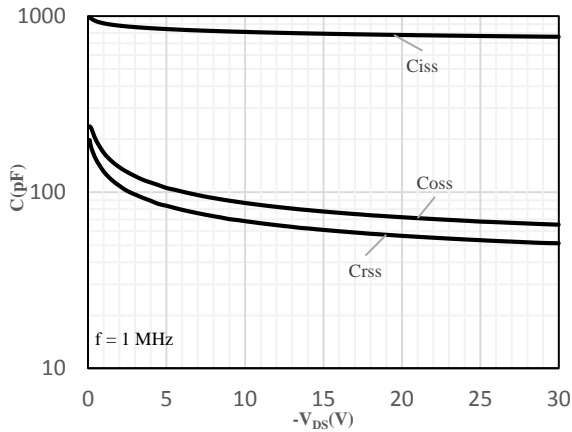


Fig 7 Capacitance Characteristics

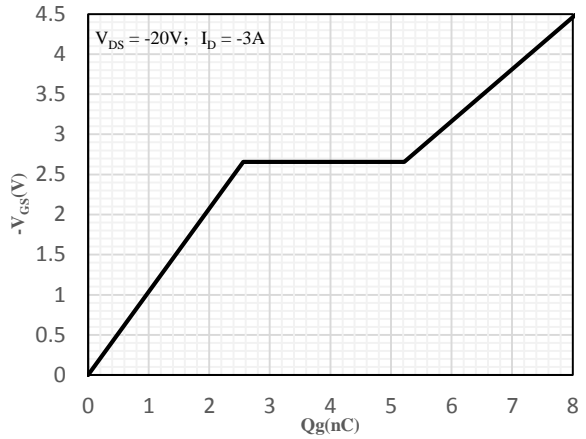


Fig 8 Gate-Charge Characteristics

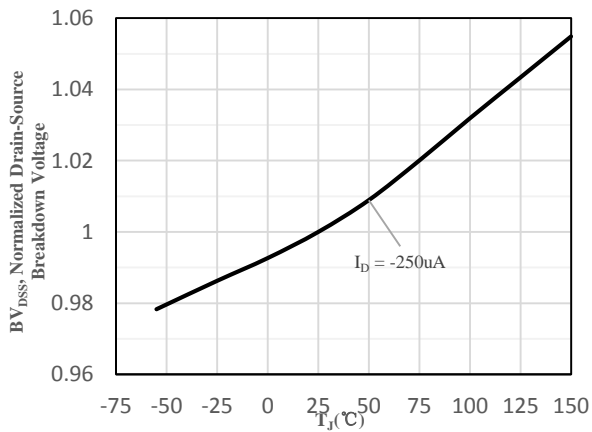


Fig 9 Normalized Breakdown Voltage vs. Junction Temperature

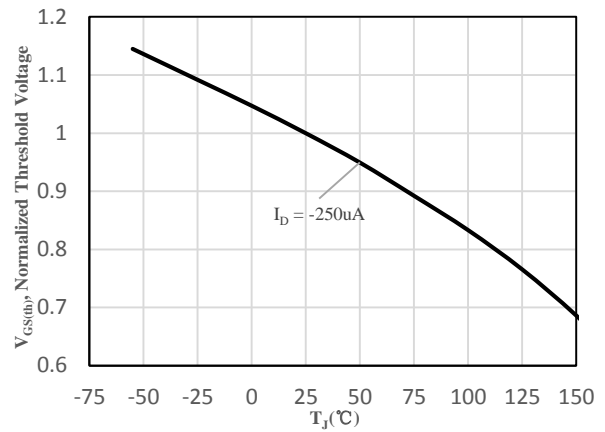


Fig 10 Normalized V<sub>GS(th)</sub> vs. Junction Temperature

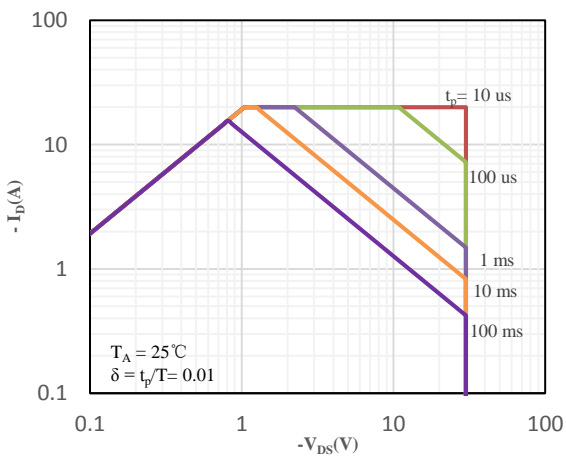


Fig 11 Safe Operation Area

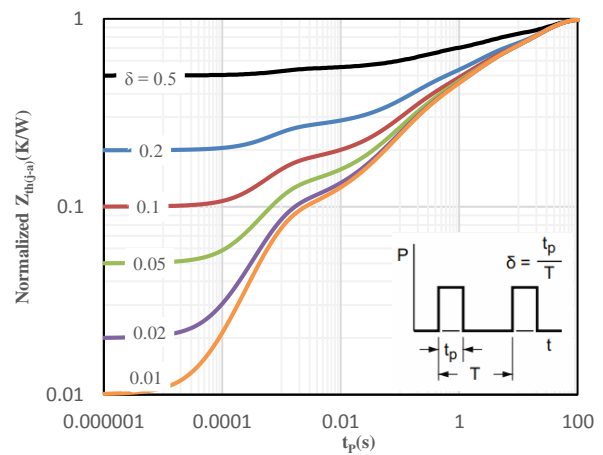
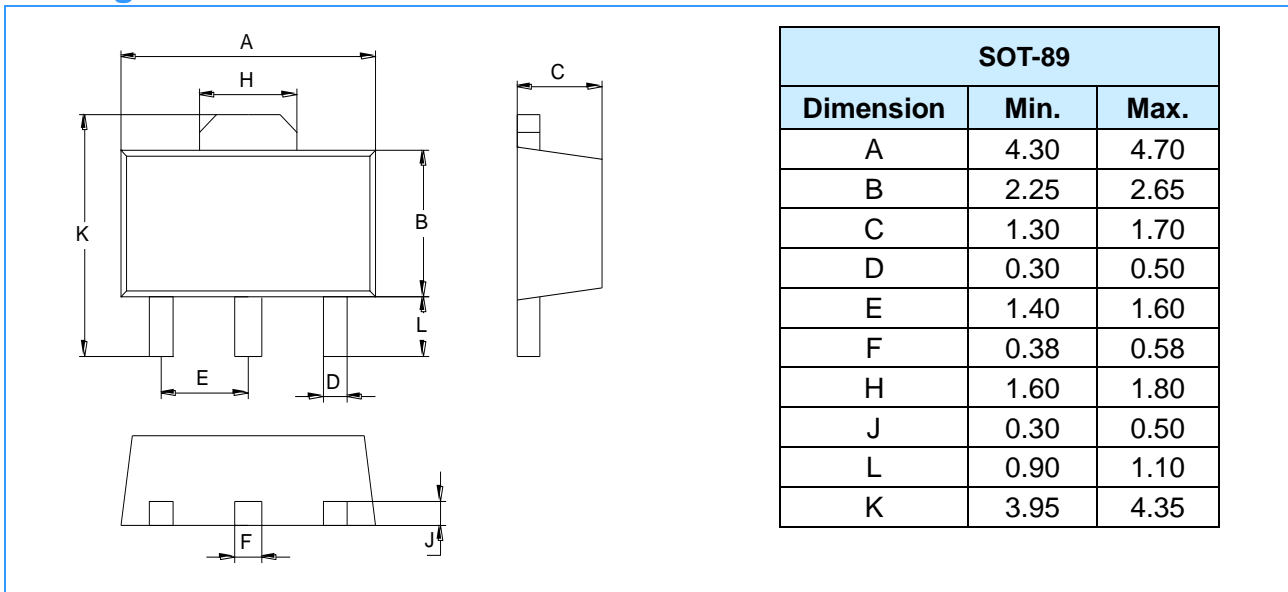
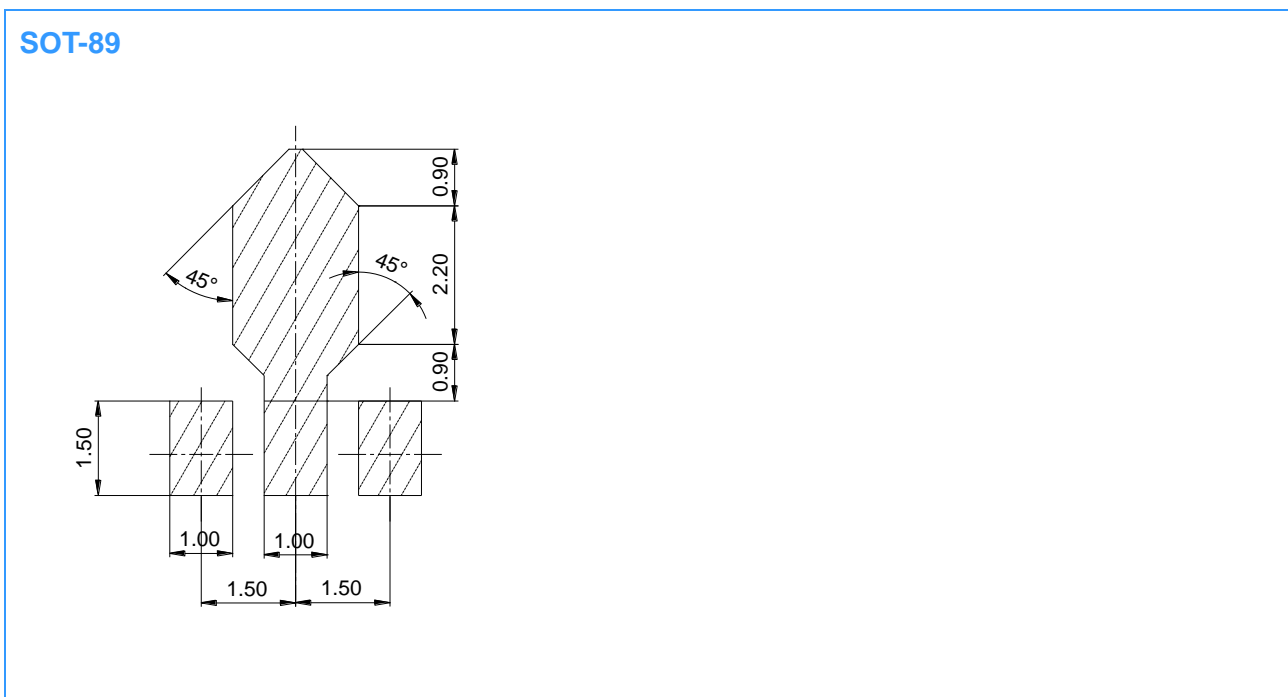


Fig 12 Normalized Maximum transient thermal impedance

**Package Outline Dimensions** (Unit: mm)



**Mounting Pad Layout** (Unit: mm)



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